

**Notice of References Cited**

Application/Control No.

10/690,330

Applicant(s)/Patent Under  
Reexamination  
KIM ET AL.

Examiner

FEBEN HAILE

Art Unit

2616

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,274,695	09-2007	Kim et al.	370/389
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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